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Session 0: Invited papers		
0.1 Design for testability survey E.J. McCluskey, Stanford, USA		1
0.2 Диагностика неисправностей регулярных технологических структур (Fault diagnosis of regular technological structures) A.D. Zakrevski, Minsk, USSR		6
0.3 A survey on the concepts of functional level test generation J. Sziray, Budapest, Hungary		15
0.5 Методы редукции данных для диагностики неисправностей (Methods of diagnostic data compression) V. P. Tchipulis, Vladivostok, USSR		278
Session 1: Design of fault-tolerant systems		
1.1 Highly reliable digital signal processor with simultaneous failure tolerance M. Kameyama, T. Higuchi, Sendai, Japan		26
1.2 System architecture and Protection mechanisms of the MuTEAM multimicroprocessor R. Cardini, M. La Manna, L. Lopriore, L. Strigini, Rome-Pisa, Italy		32
1.3 Protection and error confinement in a message-passing environment: the MuTEAM kernel E. Baiardi, A. Fantechi, A. Tomasi, M. Vanneschi, Pisa, Italy		37
1.4 Reliability design of an image integration memory for a spaceborn telescope M. Gartner, Braunschweig, FRG		43
1.5 Integrated design methodology of failure tolerant system A. Ciuffoletti, L. Simoncini, Rome-Pisa, Italy		49
Session 2: Modeling and evaluation of highly reliable systems		
2.1 A comparison among four different modular redundancy techniques in a computing system P. Velardi, Rome, Italy		55
2.2 A hierarchical performance model of a fault-tolerant multimicroprocessor G. Pulkkis, L. Saloriutta, Helsinki, Finland		61
2.3 Validation methods for fail-safe or fault-tolerant computers P. Caspi, E. Pilaud, J. Pulou, Grenoble, France		68

- 2.4 Надежно-функциональная модель протокола сети ЭВМ  
(Reliability and function orientated model of a computer network protocol)  
M. Bien, A. Wabik, Wroclaw, Poland 74
- 2.5 A contribution of fuzzy set theory to reliability of digital systems  
A. Czogala, W. Pedrycz, Gliwice, Poland 81
- 2.6 The improvement of magnetic disk information retrieval using the protective redundancy  
V. Baltac, I. Tutoveanu, V. Barbuntoiu, Bucarest, Roumania 87

### Session 3: Software reliability

- 3.1 A method for arithmetic microprograms derivation  
A. Lewinski, Warwaw, Poland 93
- 3.2 Метод построения корректных программ  
(Method of writing correct programs)  
D. Avreski, V. Sirlshova, Sofia, Bulgaria 99
- 3.3 Evaluating a symmetric fault-tolerant operating system with Petri nets  
J. Aspelund, R. Linturi, Helsinki, Finland 104
- 3.4 Data flow in program testing  
B. Korel, Katowice, Poland 112

### Session 4: Test generation

- 4.1 The functional d-algorithm. Part I.  
S. Várszegi, Budapest, Hungary 118
- 4.2 Adaptive random test generator  
J. Rada, Prague, Czechoslovakia 123
- 4.3 A practical method for generating the minimal set of tests of the combinational circuits  
F. Momeo, M. Balan, Bucarest, Roumania 128
- 4.4 Обнаружение неисправностей последовательного автомата на основе полутактовой модели  
(Fault detection in sequential circuits via half-tact model)  
V.O. Vasyukevich, A.Yu. Gobzemiz, O.S. Denisenko, A.N. Sklyarevich, Riga, USSR 133
- 4.5 Временные булевы дифференциалы и их применение в диагностике последовательных схем  
(Time Boolean difference and its application to the diagnosis of sequential circuits)  
Yu.A. Skobtsov, Donetsk, USSR 138

4.6	Представления дискретных автоматов (Representation of discrete automata) I.S. Grunski, Donetsk, USSR	142
4.7	Поиск минимальных распознающих слов для конечного автомата (On finding the minimal distinguishing sequences for finite automaton) V.G. Skobelev, Donetsk, USSR	143
Session 5: Test simulation		
5.1	Modeling the detection time of failures affecting the girth of a CPU die B. Courtois, P. Marchal, Grenoble, France	151
5.2	Bidirectional simulation - a new approach to test generation D. Reinert, Karl-Marx-Stadt, GDR	157
5.3	A deductive simulation for multiple-fault in logic circuits K. Sapiecha, K. Walczak, Warsaw, Poland	163
5.4	Graphic language for switching circuits function description J. Piotrowski, Poznan, Poland	169
Session 6: Testable design		
6.1	Remarks on untestable lines in sequential circuits E. Hübel, Ilmenau, GDR	175
6.2	Inserting test points for simple test generation W. Coy, A. Vogel, Bremen, Bonn, FRG	180
Session 7: Self-testing systems		
7.1	The algorithm for determining concurrent self-diagnosis of multiprocessor systems H. Krawczyk, Gdansk, Poland	188
7.2	Self-diagnosis in multimicroprocessor systems: the MuTEAM approach P. Ciompi, F. Grandoni, L. Simoncini, Pisa, Italy	193
7.3	Self-testing microprocessor devices E. Michta, Zielona Gora, Poland	200
7.4	The use of diagnostic timers F. Novak, Ljubljana, Yugoslavia	205

## Session 8: System diagnostics

- 8.1 The LMDS-Fault location microdiagnostic system  
J. Zelený, Prague, Czechoslovakia 211
- 8.2 The structure and properties of the LMDS tests  
A. Pluháček, Prague, Czechoslovakia 216
- 8.3 A hardware approach to the error diagnostics  
of a medium size Romanian computer  
G. Samoila, Bucurest, Roumania 221
- 8.4 Testování CNC systémů Tesla  
(Testing of the CNC systems TESLA)  
P. Žák, Kolín, Czechoslovakia 223
- 8.5 Realizace diagnostiky grafických systémů  
(Implementation of diagnostics in graphical  
systems)  
J. Smíšek, Prague, Czechoslovakia 228

## Session 9: Self-checking checkers

- 9.1 Design of self-checking checker for 1-out-of-n  
code  
V. Rabara, Žilina, Czechoslovakia 234
- 9.2 Design of totally self-checking check circuits  
for some 1-out-of-n codes  
M. Kotočová, Bratislava, Czechoslovakia 241
- 9.3 A new totally self-checking checker  
for 1-out-of-3 code  
P. Golan, Prague, Czechoslovakia 246

## Session 10: Diagnostic devices and systems

- 10.1 Automatic test system ADT/ZKD  
P. Štolle, Prague, Czechoslovakia 249
- 10.2 Lokalizace poruch pomocí testovacího  
systému ADT/ZKD  
(Fault location with the test system ADT/ZKD)  
V. Škvor, Prague, Czechoslovakia 254
- 10.3 IC classification on the printed circuit board  
J. Reviczky, Budapest, Hungary 259
- 10.4 Board testing strategy and tool for hardware  
development  
B. Csabai, G. Dénes, L. Harmat, A. Reszler,  
J. Romhányi, Budapest, Hungary 264
- 10.5 Logic state analyzer ANISS-20  
K. Swierc, Katowice, Poland 266
- 10.6 The method of increasing the probability of  
detecting errors for signature analysis  
A. Hlawiczka, H. Kubica, Gliwice, Poland 273